

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : Unknown
Serial No. : New Divisional Application Examiner : Unknown
Filed : January 9, 2004 Confirmation No.: Unknown
Title : SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE SAME

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Under 35 USC §120, this application relies on the earlier filing date of application serial number 10/107,113, filed on March 26, 2002. The references on the attached list were submitted to and/or cited by the Office in the prior application and, therefore, are not provided in this application.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: January 9, 2004


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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-218003	Application No. New Divisional Appln.
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.	
		Filing Date January 9, 2004	Group Art Unit Unknown

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,170,244	12/08/92	Dohjo, et al.			
	AB	5,250,931	10/05/93	Misawa, et al.			
	AC	5,525,822	06/11/96	Vinal			
	AD	5,744,824	04/28/98	Kousai, et al.			
	AE	5,780,872	07/14/98	Misawa, et al.			
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	AG	5,821,138	10/13/98	Yamazaki, et al.			
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	AQ	2001/0018224	08/30/01	Zhang			
	AR						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AS	1118521	03/13/96	China			ABS
	AT	JP 07-135318	05/23/95	Japan			ABS
	AU	JP 08-078329	03/22/96	Japan			ABS
	AV	JP 08 213634	08/20/96	Japan			ABS
	AW	JP 08 288522	11/01/96	Japan			ABS
	AX	JP 09-022077	01/20/97	Japan			Full

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AY	JP 09-312260	12/02/97	Japan			ABS
	AZ	JP 10-270363	10/09/98	Japan			ABS

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	BA	Kuznetsov, et al., "Silicide precipitate formation and solid phase regrowth of Ni+-implanted amorphous silicon", Inst. Phys. Conf. Ser. No. 134:Section 4, Paper presented at Microsc. Semicond. Mater. Conf., April 1993, pp. 191-194.
	BB	Kuznetsov, et al., "Transient kinetics in solid phase epitaxy of Ni doped amorphous silicon", Nuclear Instruments & Methods in Physics Research, B 96, 1995, pp. 261-264.
	BC	
	BD	

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